# Application/Control No. O9/931,708 Examiner Eric M Williams Applicant(s)/Patent Under Reexamination REIK ET AL. Art Unit Page 1 of 1

# Notice of References Cited

### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,450,314	09-2002	Jackel et al.	192/70.17
	В	US-6,360,863	03-2002	Young, Alastair John	192/85CA
	С	US-6,354,188	03-2002	Tobiasz, Andre	92/107
	D	US-6,260,683	07-2001	Rohs et al.	192/70.17
	Е	US-6,244,409	06-2001	Winkelmann et al.	192/85CA
	F	US-5,577,585	11-1996	Corral, Cecilio M.	192/91A
	G	US-5,398,796	03-1995	Doremus, Olivier	192/85CA
	Н	US-5,273,145	12-1993	Corral et al.	192/91A
	ı	US-5,205,387	04-1993	Checa, Eduardo A.	192/85CA
	J	US-4,995,492	02-1991	Babcock et al.	192/85CA
	К	US-4,729,464	03-1988	Friedmann, Oswald	192/70.17
	L	US-5,284,233	02-1994	Feigler, Jacques	192/98
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Ρ					
	σ					
	R					
	S					
	Т					

### **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.